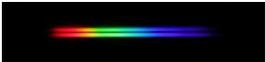
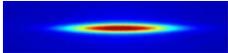
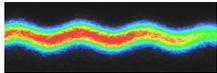
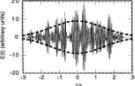


Beam Size Measurements with Synchrotron Radiation - An Overview

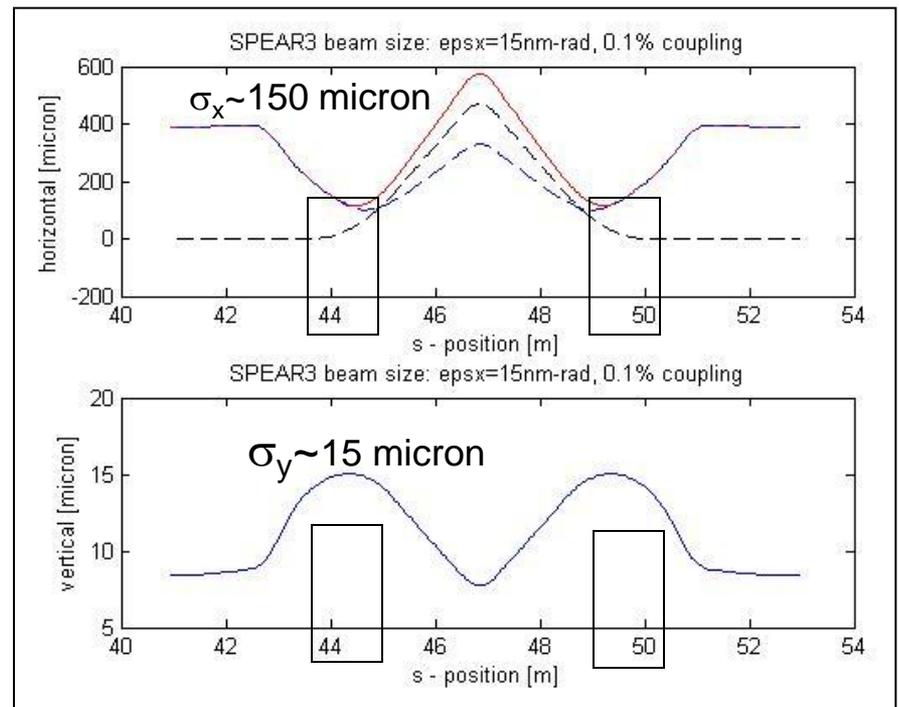
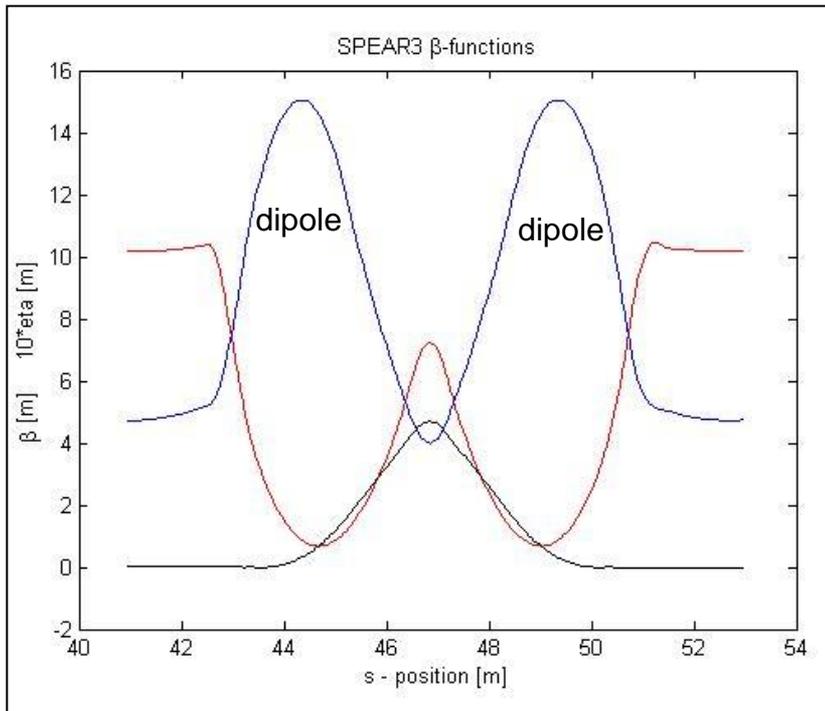
Jeff Corbett, Alan Fisher and Walter Mok
US Particle Accelerator School
January 14-18, 2008

- Motivation
- Electron beam properties
- SR beam properties
- Standard imaging – visible spectrum  $\lambda=550\text{nm}$
- X-ray pinhole camera 
- Fast imaging – gated ICCD and streak cameras 
- Interferometer & vertical polarization
- Fluctuation measurements 

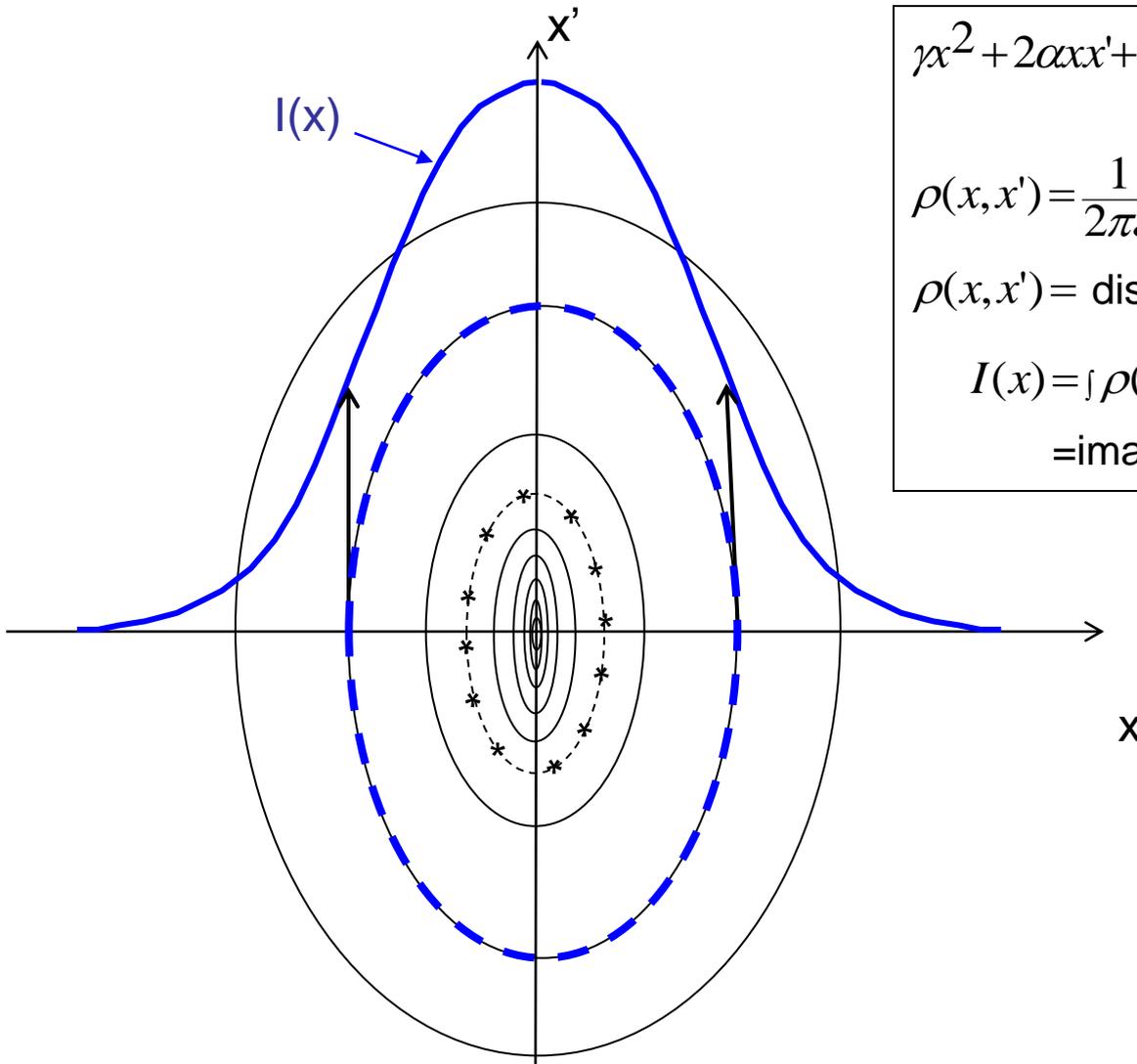
Motivations for beam size measurements

- 'eye' into the accelerator
- faithful photon image reproduces electron beam (x,y,z)
- optics verification, coupling, brightness
- impedance and instabilities
- other techniques less accurate (e.g. scraper, RMA)

Electron beam properties: β -functions and beam size



Electron beam properties: Phase Space



$\gamma x^2 + 2\alpha x x' + \beta x'^2 = \text{invariant oscillation amplitude}$

$$\rho(x, x') = \frac{1}{2\pi\varepsilon} e^{-(\gamma x^2 + 2\alpha x x' + \beta x'^2)/2\varepsilon}$$

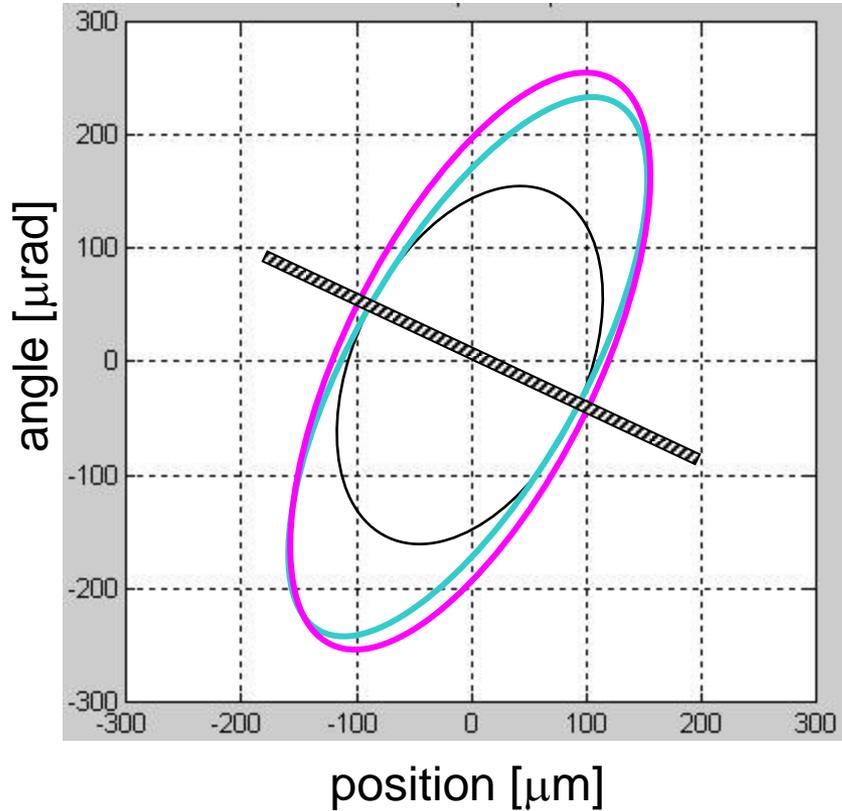
$\rho(x, x') = \text{distribution in phase space}$

$$I(x) = \int \rho(x, x') dx' = A e^{-x^2/2\varepsilon\beta}$$

= image projected on screen

Photon beam properties: Phase Space

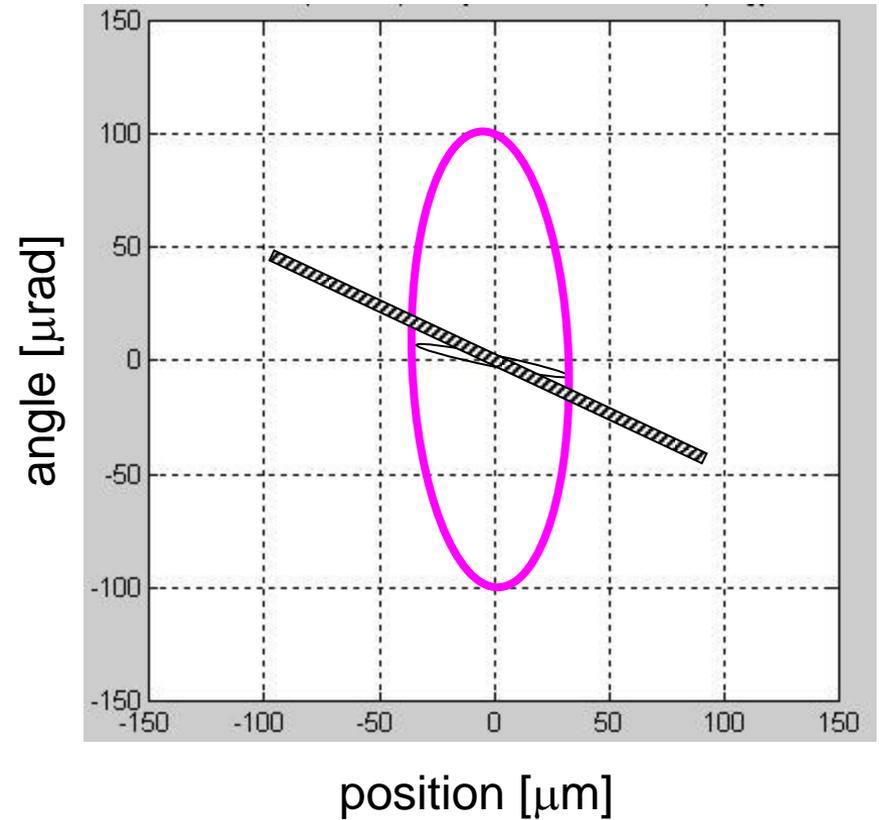
SPEAR3: Horizontal



$$\sigma_x^2 = \varepsilon_x \beta_x + (\eta_x \delta)^2$$

$$\sigma_{x'}^2 = \varepsilon_x \gamma_x + (\eta'_x \delta)^2 + \sigma_r^2$$

SPEAR3: Vertical

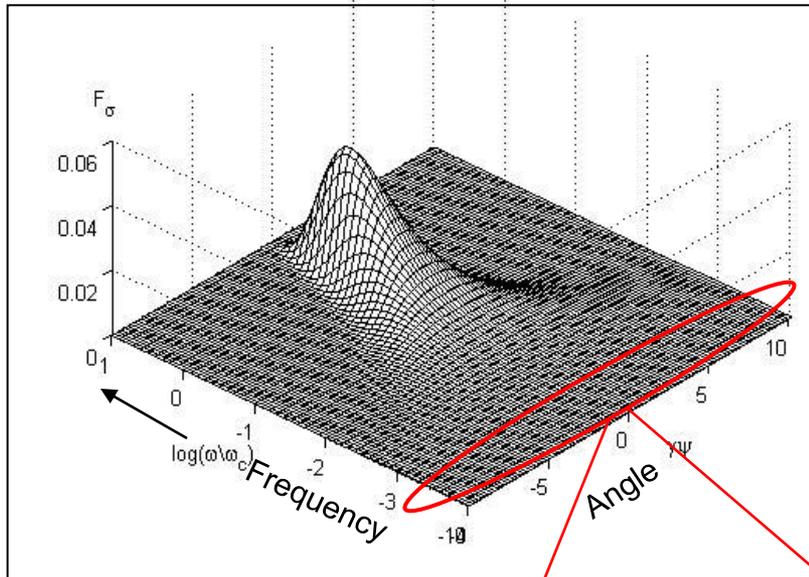


$$\sigma_y^2 = \varepsilon_y \beta_y + (\eta_y \delta)^2$$

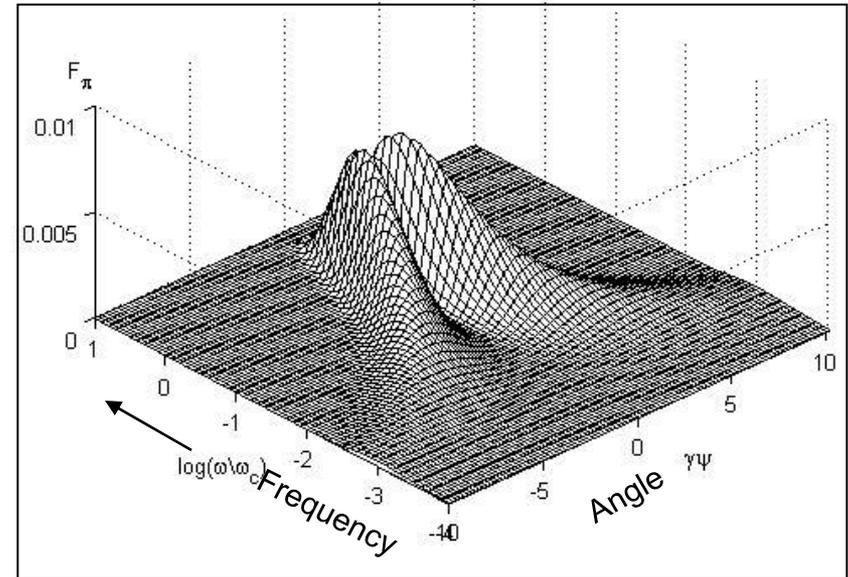
$$\sigma_{y'}^2 = \varepsilon_y \gamma_y + (\eta'_y \delta)^2 + \sigma_r^2$$

Photon beam properties: Angular spectral power density

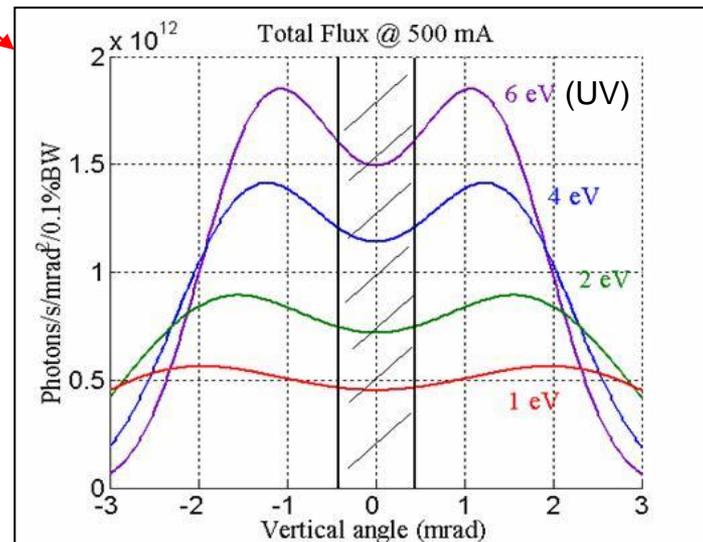
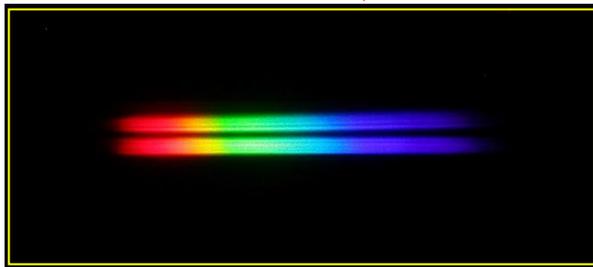
Horizontal Polarization



Vertical Polarization



visible component



Photon beam properties: Beam power

Example:

3 GeV and 200 ma current

$P_{SR} \sim 200\text{kW}$ (total)

visible beam line (1.5eV)

25mm aperture at 5 m (5 mrad)

$P_{SR} \sim 150\text{W}$

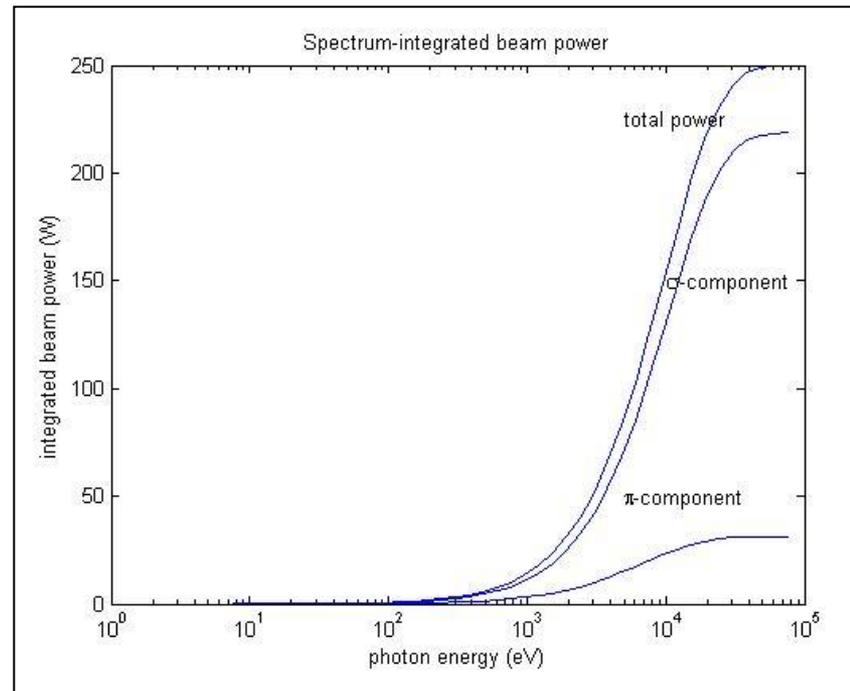
lucky to get 100 μW visible

(Class I laser pointer)

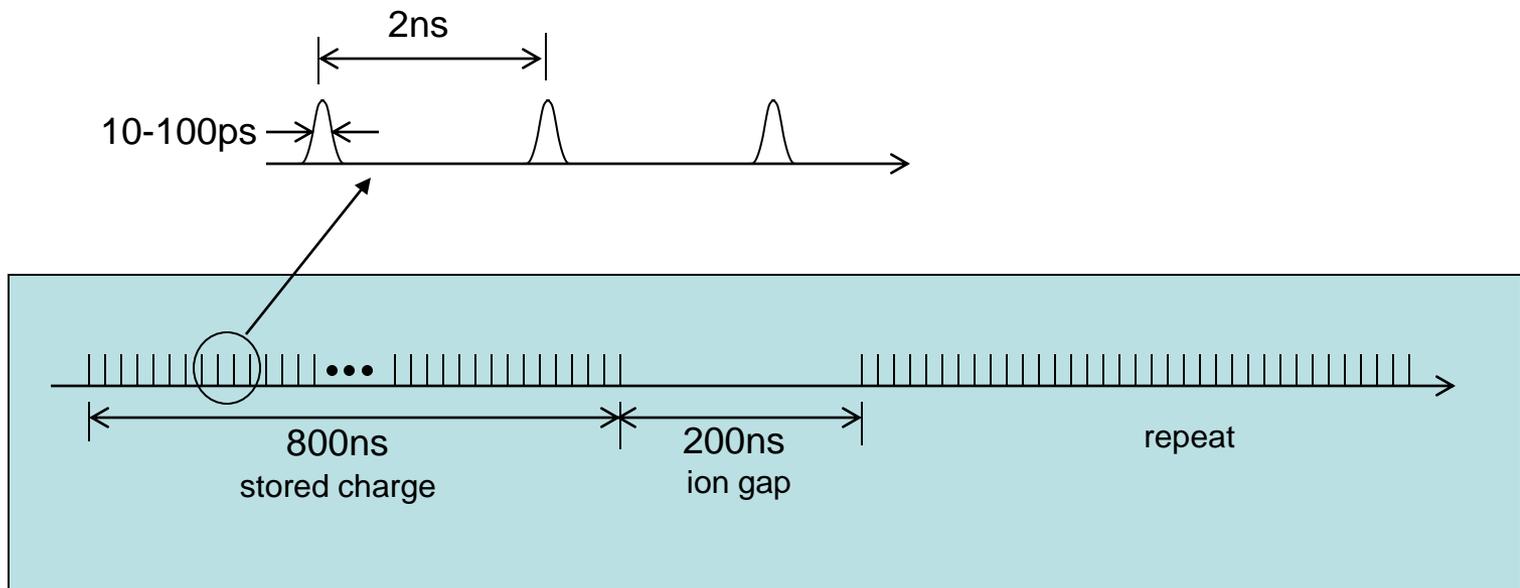
pinhole camera (15keV)

25 μm aperture at 5 m (5 μrad)

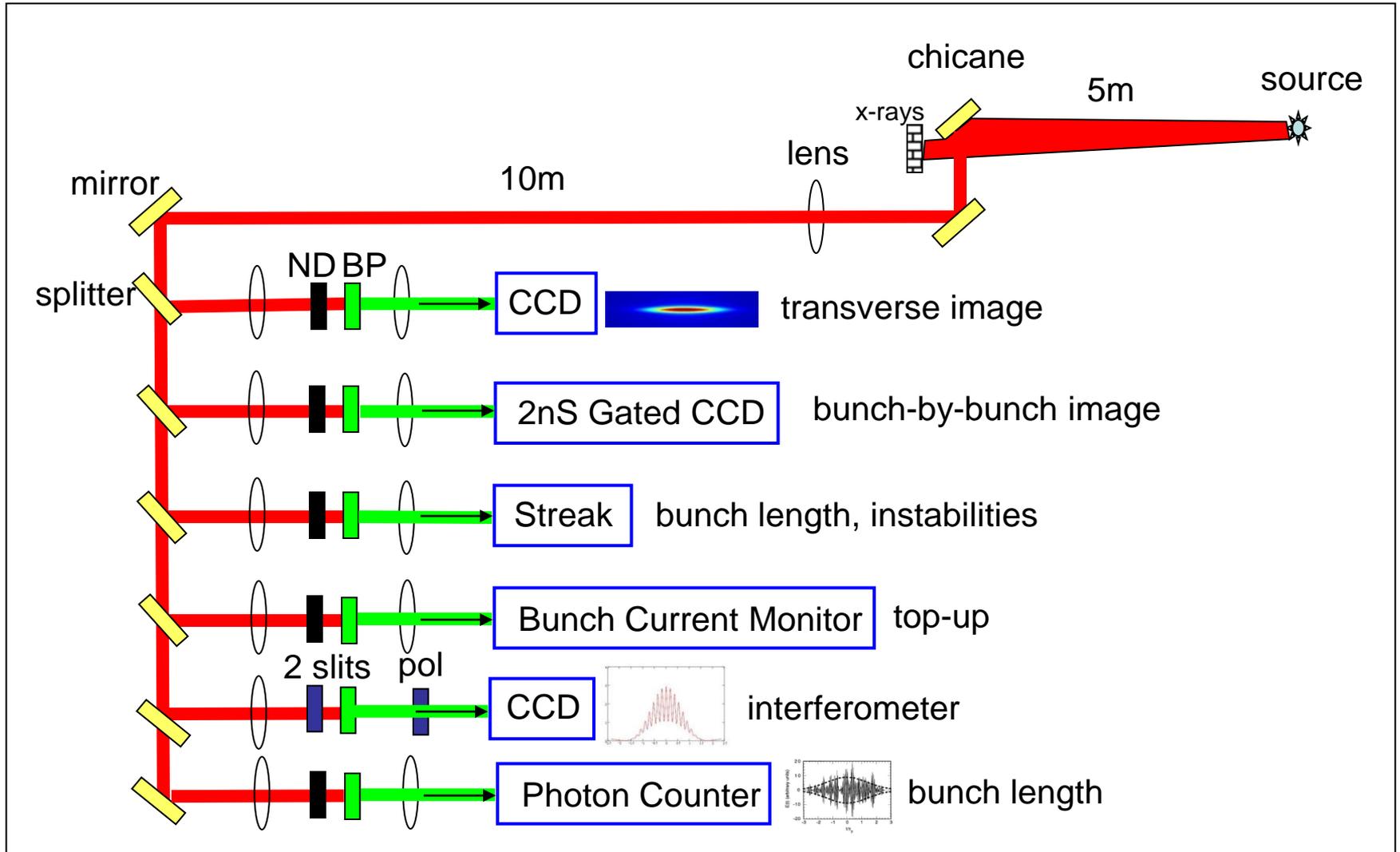
$P_{SR} \sim 100\mu\text{W}$ before filter



Photon beam timing pattern - storage rings



Visible beam line components



Visible beam line components (cont'd)

Beam line optics

Windows - quartz can pass down to about 220nm

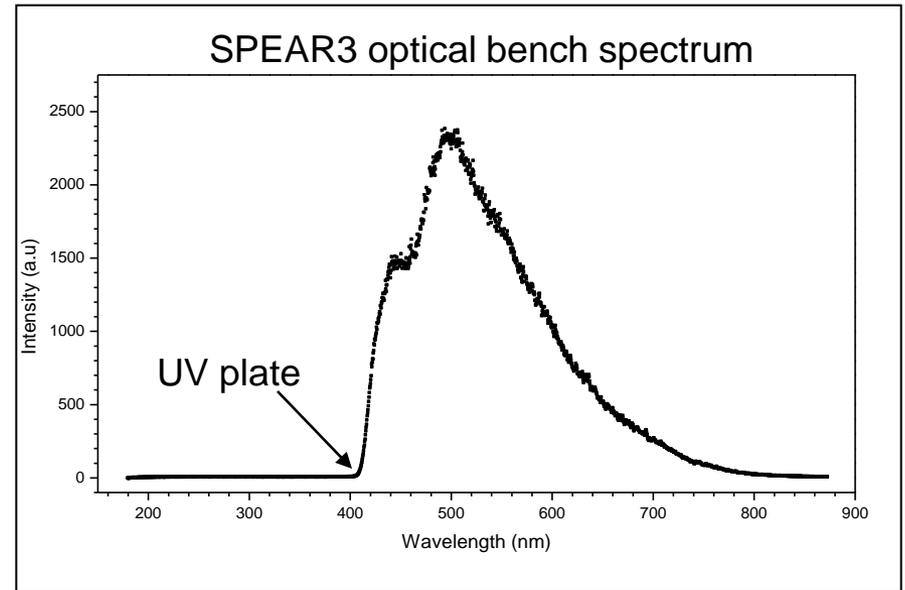
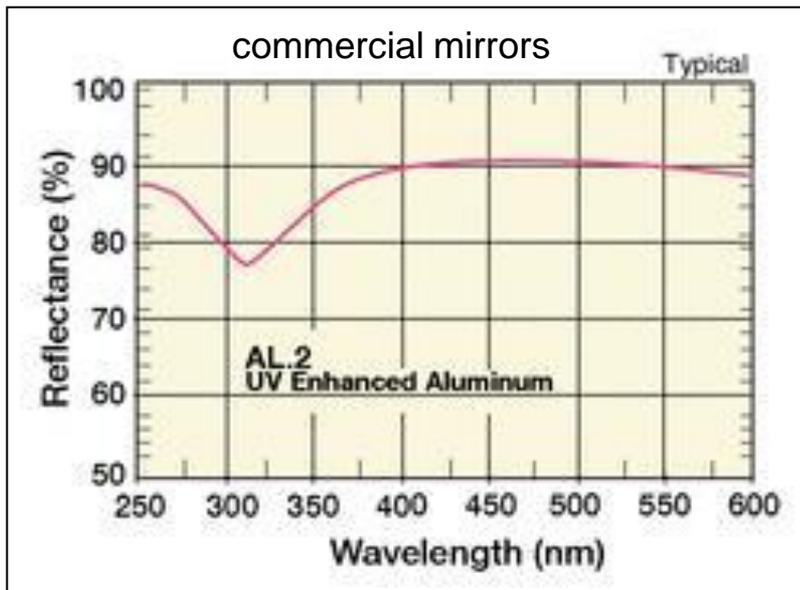
Mirrors – flat or focusing, UV enhanced

Lenses – focusing, defocusing, doublets, achromats >350nm

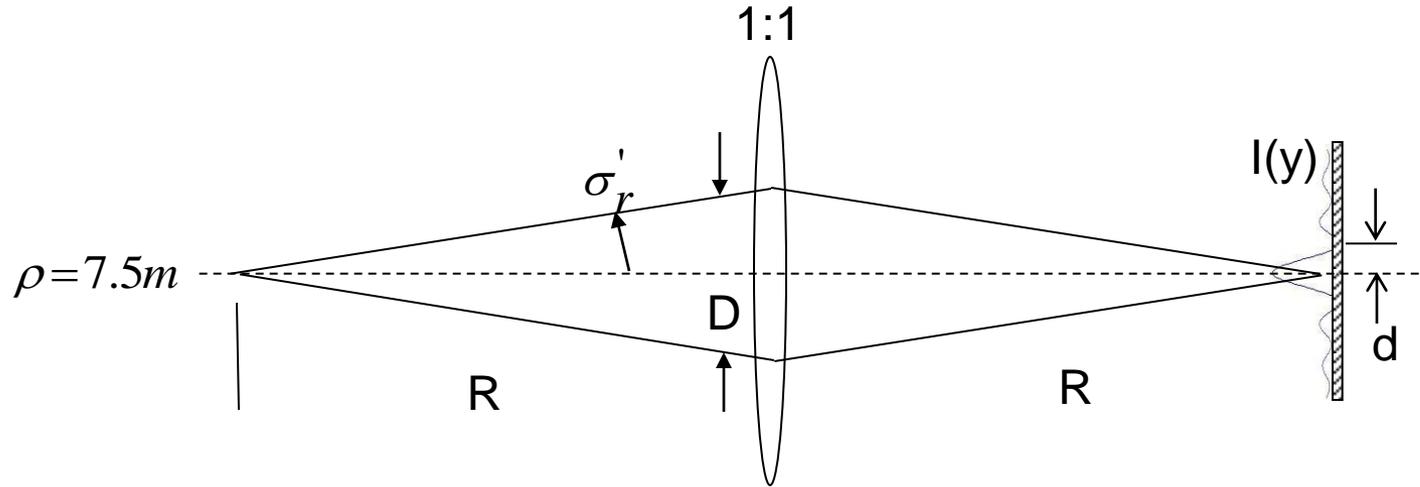
Filters –highpass and bandwidth to about 10nm FWHM

Slits and diaphragms – 1ms mechanical shutters, 10ps Pockel cells

About 90% transmission per element



Diffraction Limited Resolution



For lens aperture:

$$d \approx \frac{\lambda R}{2D}$$

where for SR

$$D = 2\sigma'_r R$$

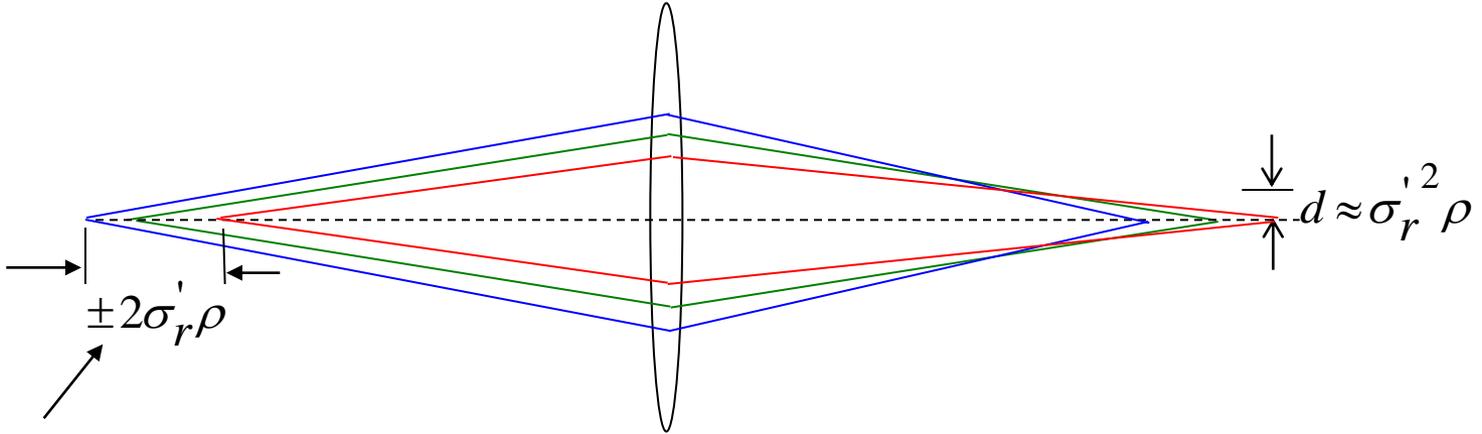
$$\sigma'_r = 0.41 \cdot (\lambda / \rho)^{1/3} \quad \text{visible}$$

$$d \approx \frac{1}{3} \cdot (\lambda^2 \rho)^{1/3}$$

$$d \approx 40\mu\text{m} \quad \text{at } \lambda = 550\text{nm}$$

more diffraction later...

Depth of Field



bend angle effect

$$d \approx \sigma_r',2 \rho$$

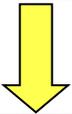
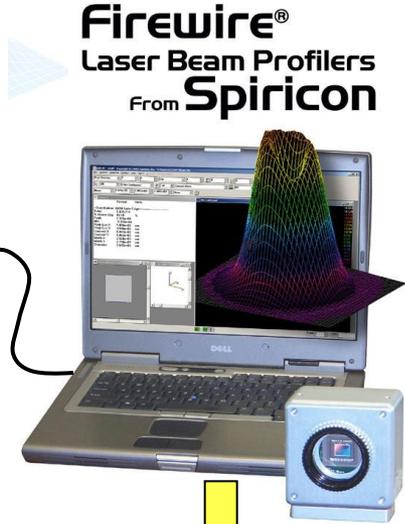
$$d \approx \frac{1}{3} \cdot (\lambda^2 \rho)^{1/3}$$

~same result as diffraction
(source length related to opening angle)

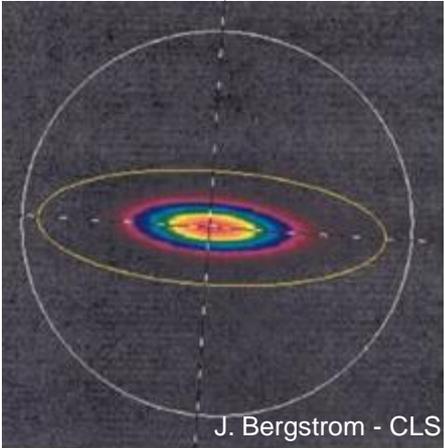
Cameras I: CCD's and Video



Frame Grabber



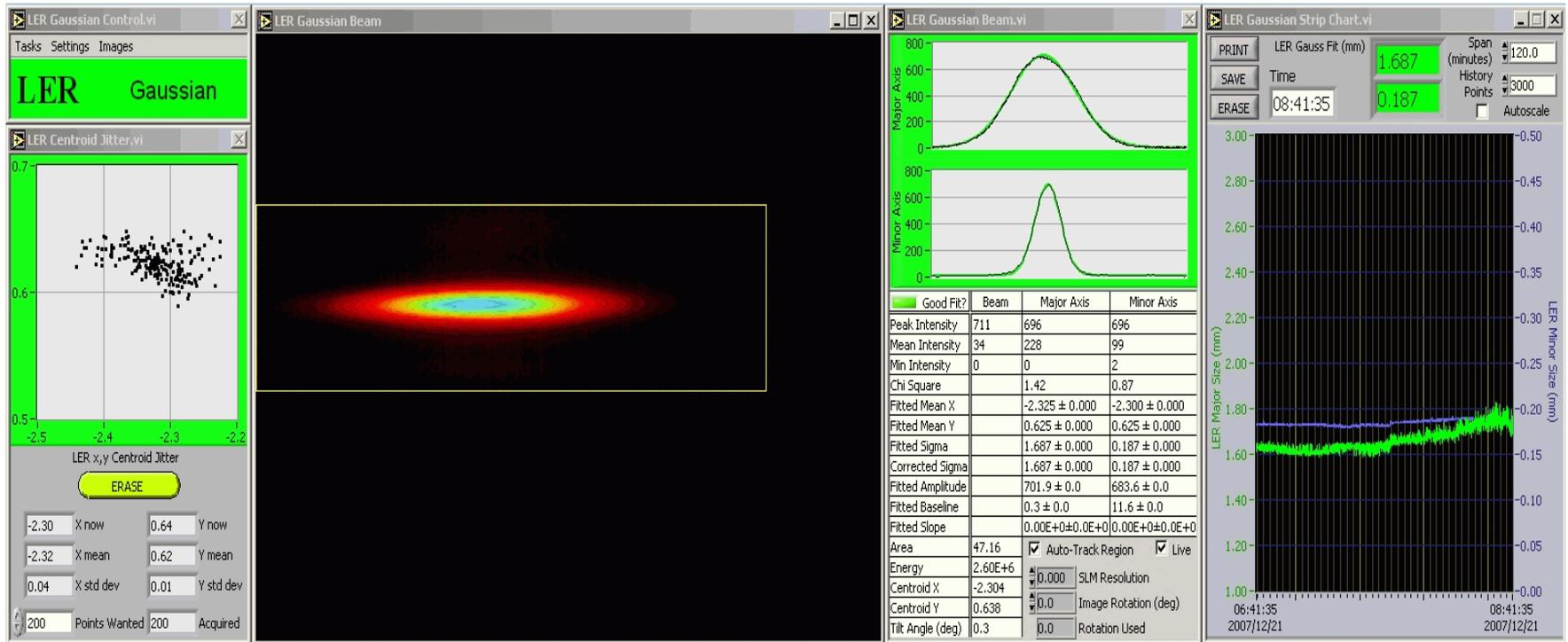
EPICS, MATLAB



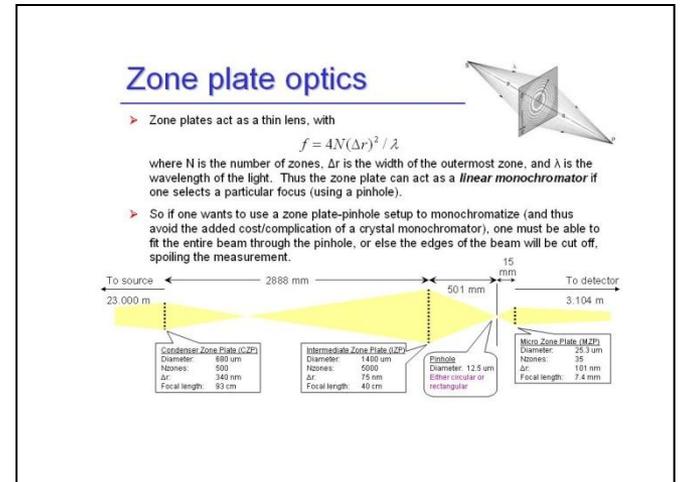
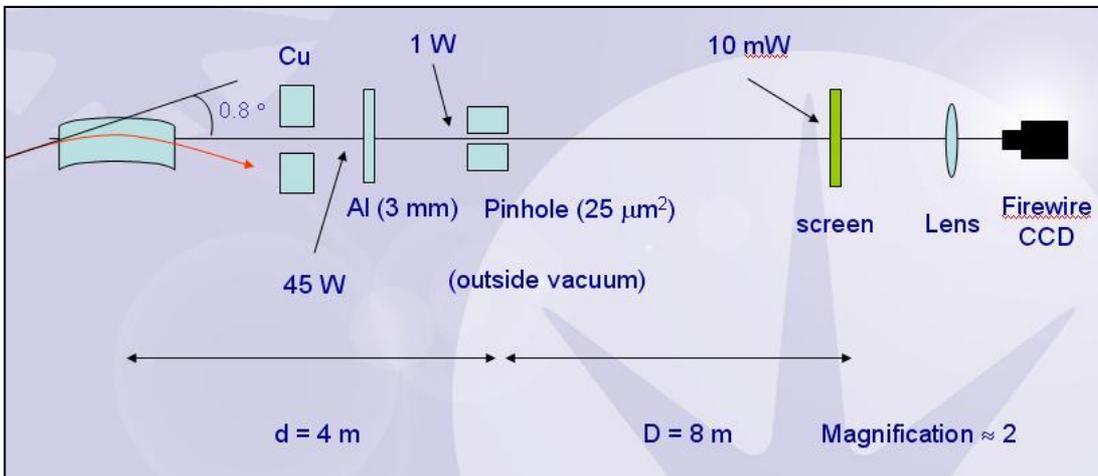
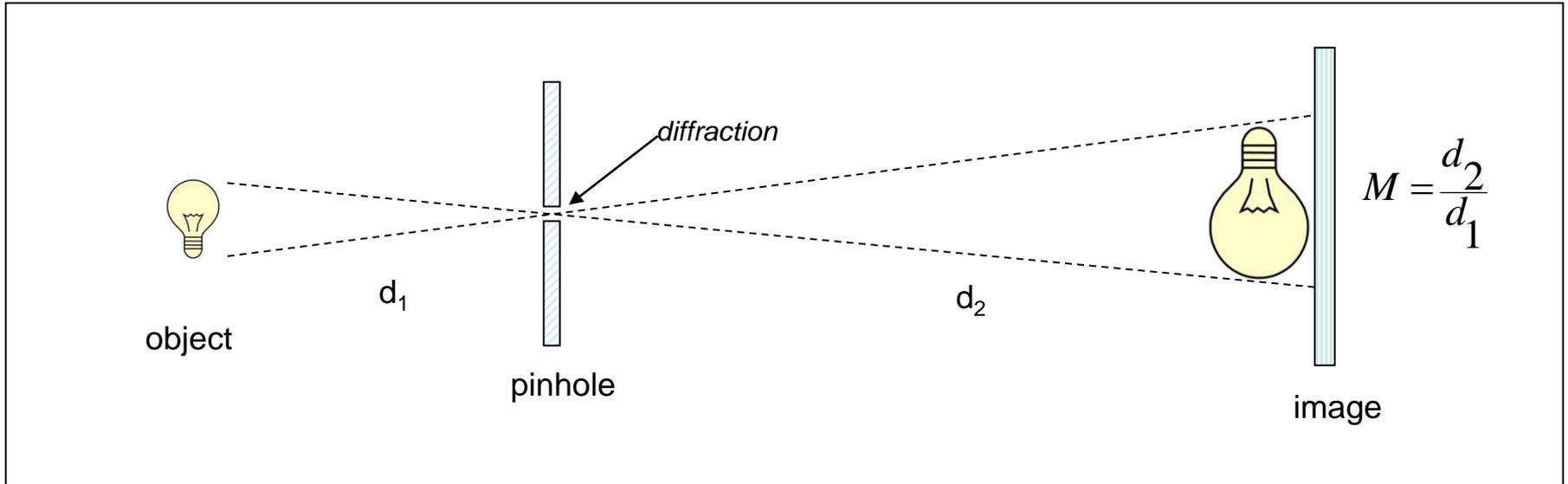
J. Bergstrom - CLS

Beamspot at XSR

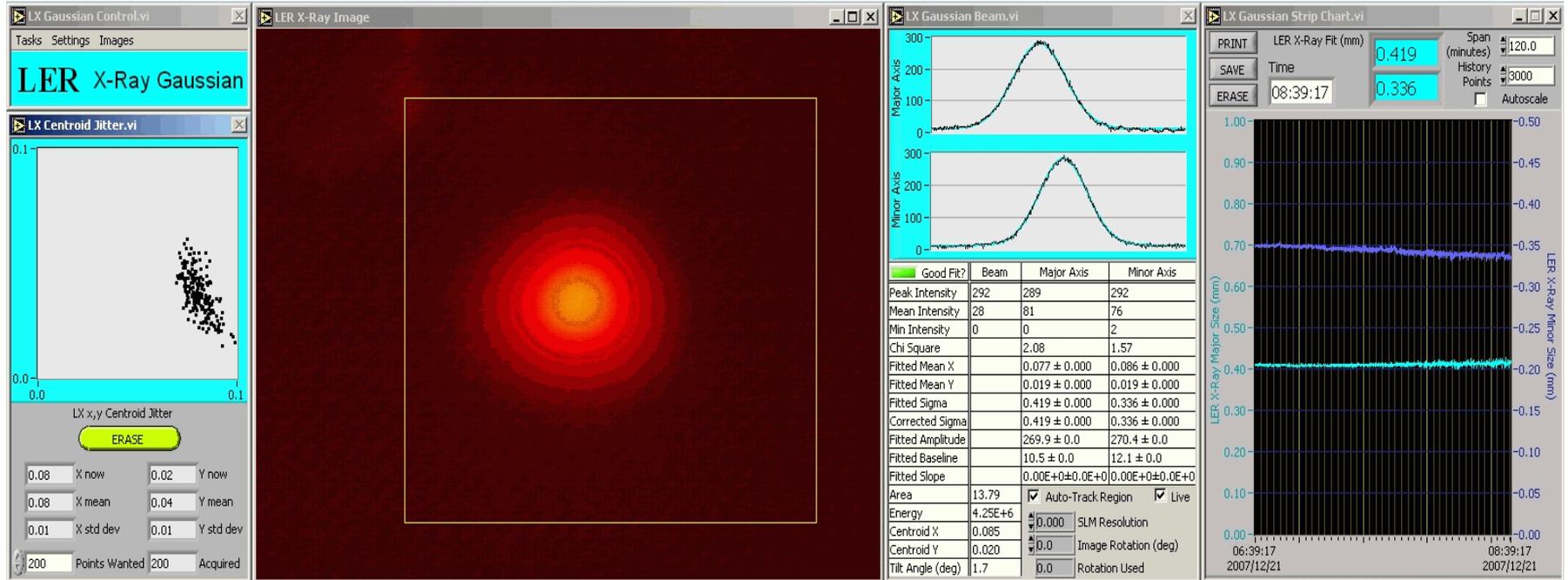
PEP-II: visible light monitor software (LabView)



X-ray pinhole cameras - Reduce diffraction with small λ



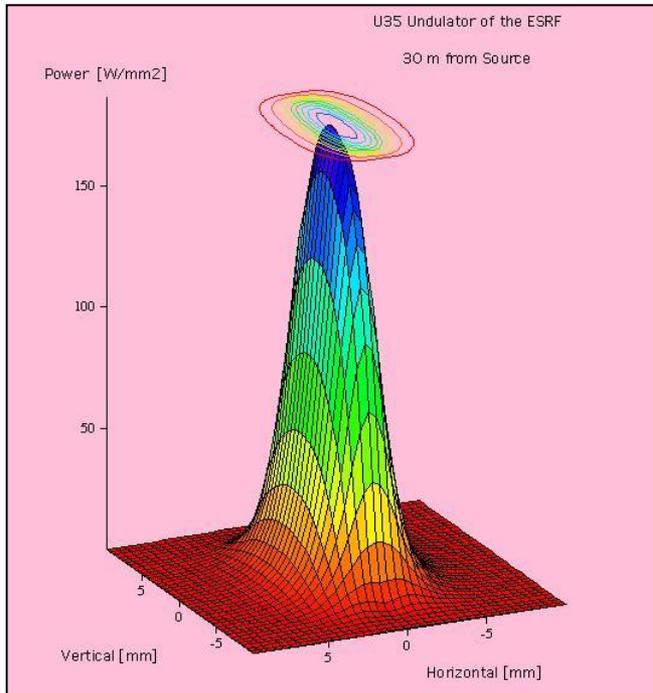
PEP-II: x-ray pinhole camera software (LabView)



Photon beam propagation programs

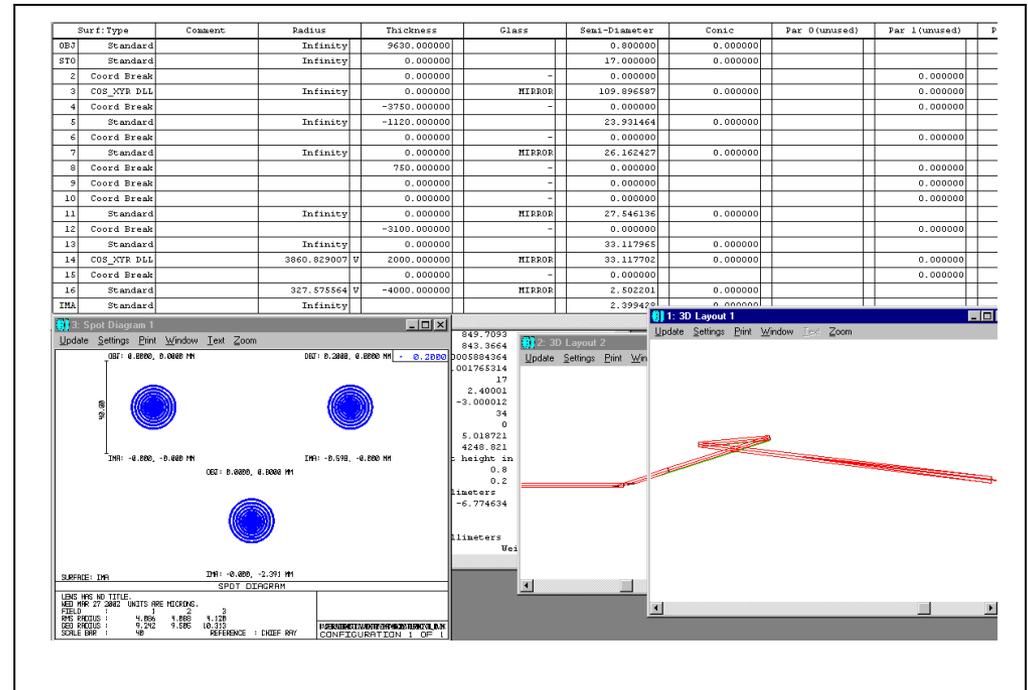
SRW

(synchrotron radiation workshop)



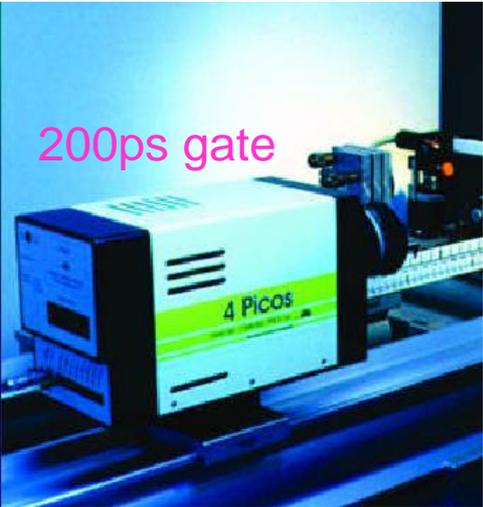
Zemax

(commercial product)

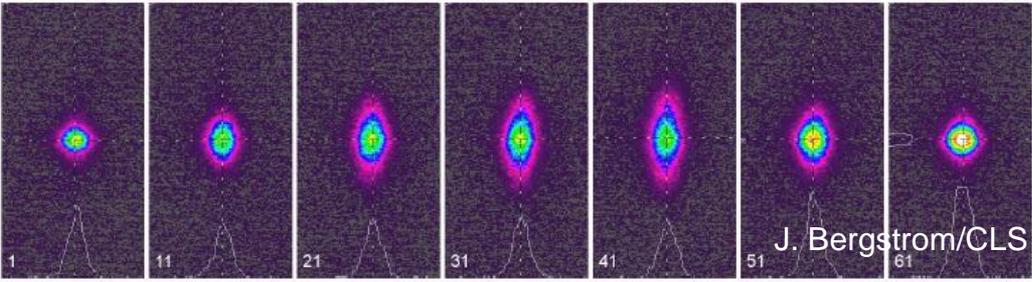
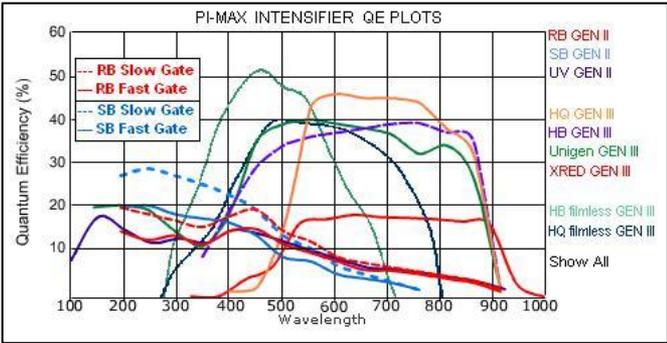


Cameras II: Gated ICCD's

Stanford 4 Picos



Roper/PiMax

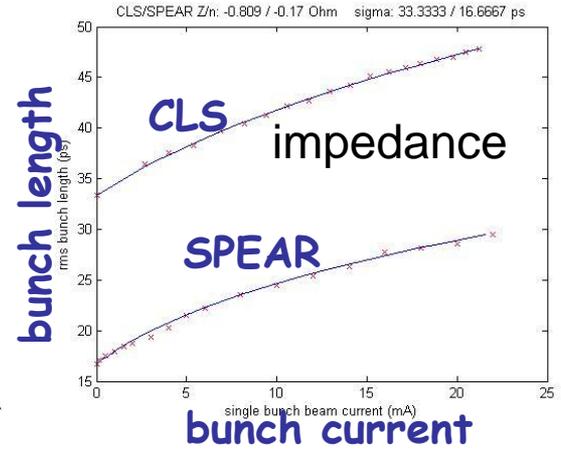
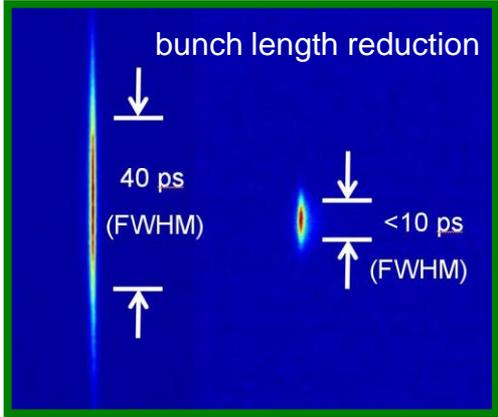


J. Bergstrom/CLS

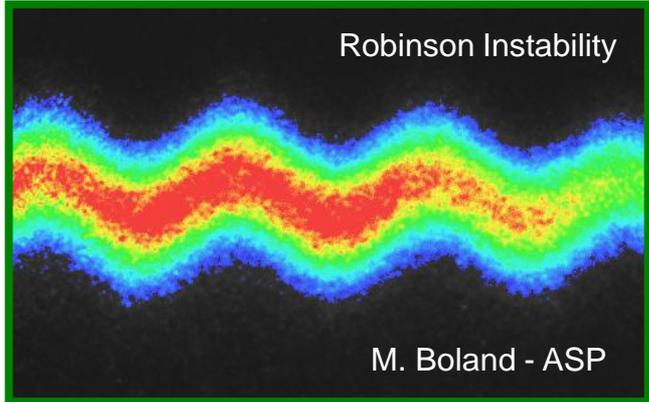
Fig. 8: Walking along a bunch train with the ICCD camera. This sequence shows every

Cameras III - Streak tubes

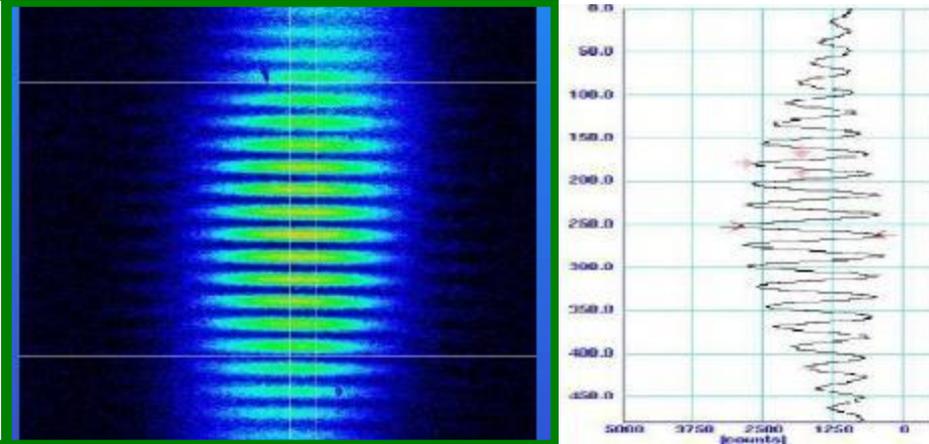
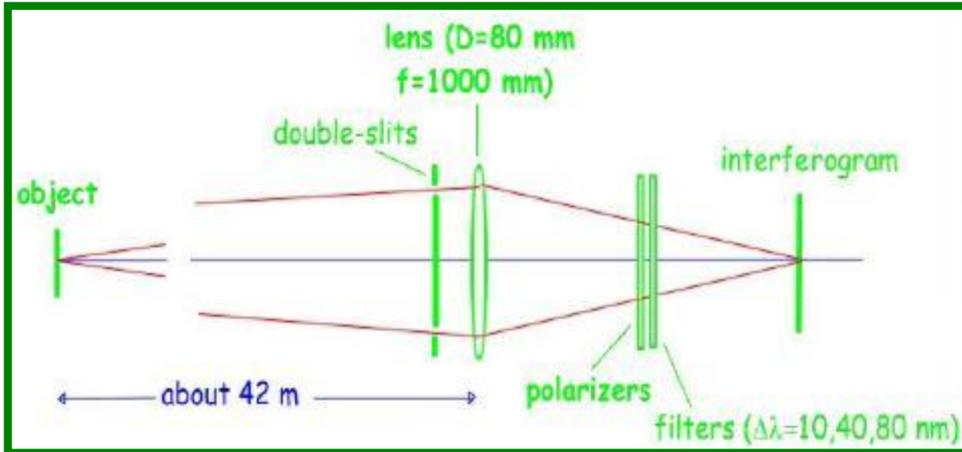
Hamamatsu C5680
Optronis (ASP)



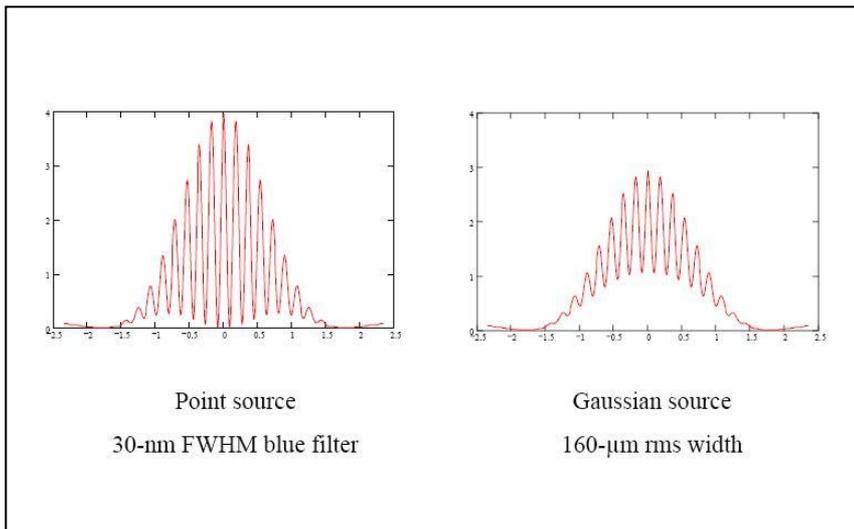
speed: up to 2 pixel/ps
chromaticity: BP filter needed
-bunch length
-impedance and instabilities



Small beam size - Interferometer technique



H. Mitsuhashi - Photon Factory



Fringe Formulas

The slits have width a and center-to-center spacing d . The pattern from a single slit is:

$$I_{\pm}(\theta) = \left[\frac{\sin \left[\frac{ka}{2} \left(\theta \mp \frac{d}{2s_0} \right) \right]}{\frac{ka}{2} \left(\theta \mp \frac{d}{2s_0} \right)} \right]^2$$

The interference from both slits at height y on the CCD, integrated over the optical bandpass filter, shows decreasing modulation with beam size:

$$I(y) = \int_{-\infty}^{\infty} \left[I_+ + I_- + 2\sqrt{I_+ I_-} \exp \left(-\frac{(kd\sigma_y)^2}{2s_0^2} \right) \cos \left(\frac{kdy}{f + \Delta z} \right) \right] g(\lambda) d\lambda$$

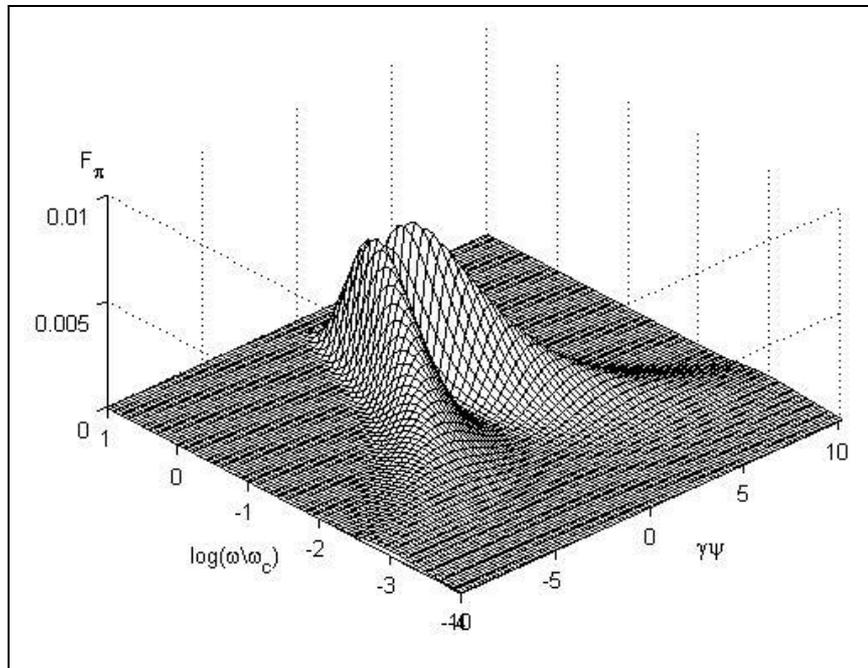
The ray leaving the slit at an angle θ hits the CCD at height y :

$$\theta_{\pm}(y) = \frac{y \pm \frac{d\Delta z}{2f}}{f + \Delta z \left(1 - \frac{\Delta s}{f} \right)}$$

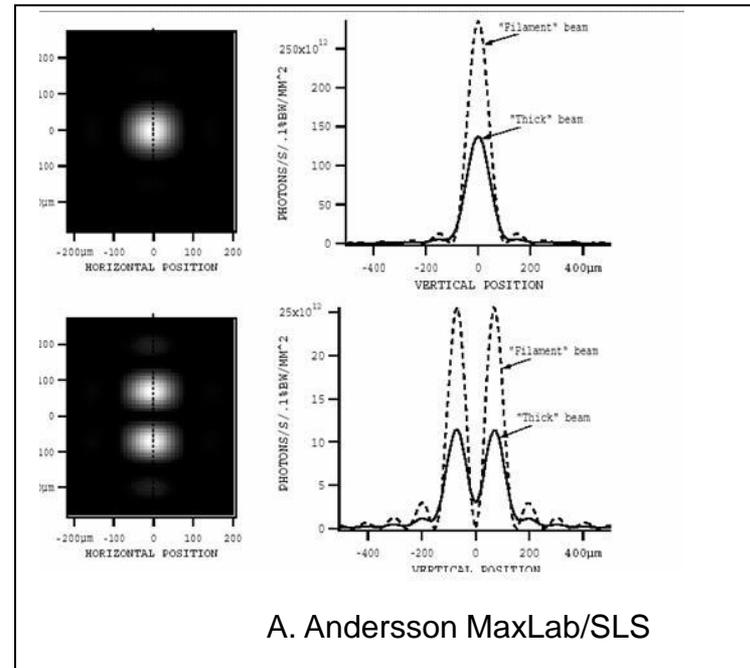
A. Fisher - SLAC

Small beam size - Vertical polarization technique

Vertical angular spectral density

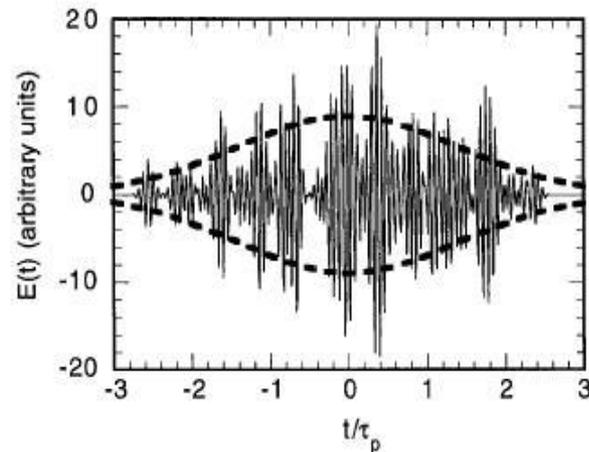


Measurements at MaxLab



Bunch Length Measurement - Statistical Fluctuations

Intra-pulse fluctuation of the electric field



$$\delta^2 = \frac{\sigma_W^2}{\langle W \rangle^2} = \int_{-\infty}^{\infty} \int_{-\infty}^{\infty} dt dt' \frac{|K(t-t')|^2}{|K(0)|^2} I(t) I(t')$$

$$\delta^2 = 1/\sqrt{1 + 4\sigma_t^2 \sigma_\omega^2}$$

Fig. 1. Electric field of a pulse of incoherent radiation as a function of time. The ratio $\Delta\omega/\omega_0 = 0.1$, and the parameter $N = 10$. The dashed lines show $\sqrt{I(t)}$.

G. Stupajkov/SLAC

Fluctuation measurements at the ALS (F. Sannibale)

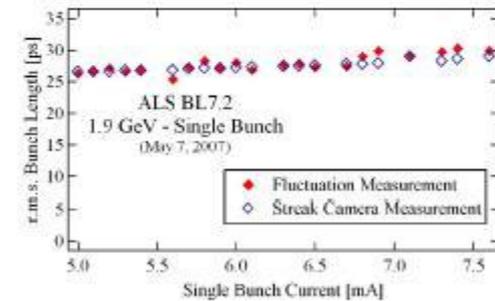
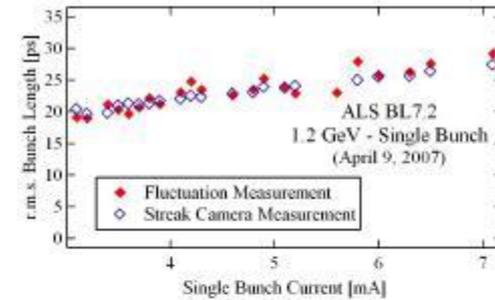
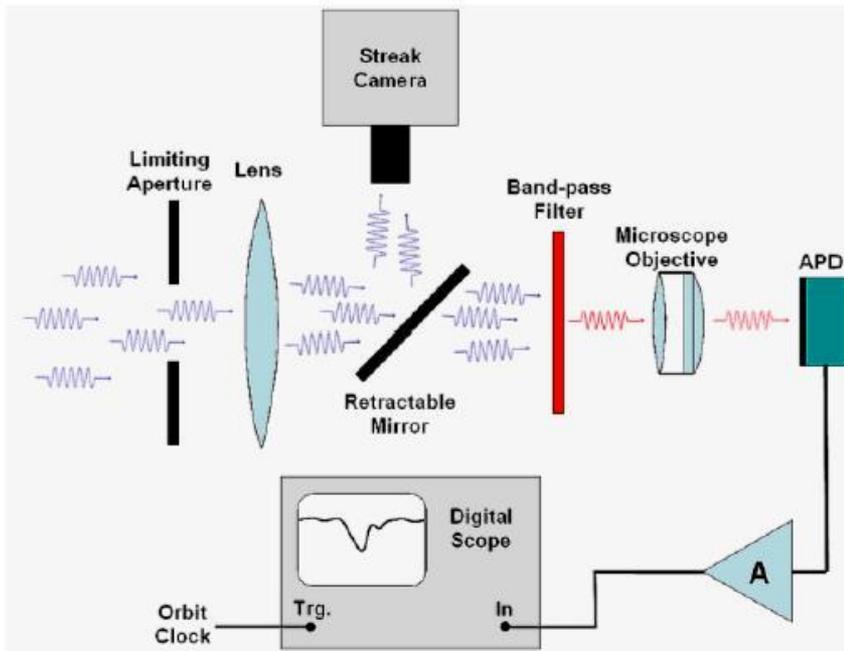


Figure 3: Examples of fluctuation and streak-camera bunch length measurements at the ALS for different beam parameters.

Summary of beam size measurements

- Photon emission provides valuable diagnostic of e^- beam
- Need to unfold γ_r , DOF, diffraction, PSF, etc. from image
- Visible has advantage of commercial optics and cameras but suffers from large γ_r and diffraction
- Broad array of cameras, fast shutters, streak frames
- X-ray pinhole has advantage of less diffraction but generally less versatile
- Interferometers and central-null technique improve resolution
- Fluctuation measurements cheaper than streak, provide insight
- other techniques:
 - screens, OTR, wires and lasers in transmission lines
 - scraper in storage ring (quantum lifetime)
 - response matrix analysis